

Notice of References Cited

Application/Control No.

09/574,541

Applicant(s)/Patent Under

Reexamination

SHIN ET AL.

Examiner

Chuong A Luu

Art Unit

2825

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
*	A	US-6268568 B1	07-2001	Kim	174	250
*	B	US-6242279 B1	06-2001	Ho et al.	438	106
*	C	US-6228676 B1	05-2001	Glenn et al.	438	107
*	D	US-6277672 B1	08-2001	Ho	438	121
*	E	US-6274404 B1	08-2001	Hirasawa et al.	438	107
*	F	US-6271057 B1	08-2001	Lee et al.	438	106
*	G	US-6261869 B1	07-2001	Radford et al.	438	123
*	H	US-6258632 B1	07-2001	Takebe	438	127
*	I	US-6093970	07-2001	Ohsawa et al.	257	777
*	J	US-6074898	06-2000	Ohsawa et al.	438	123
*	K	US-5930599	07-1999	Fujimoto et al.	438	113
*	L	US-5909633	06-1999	Haji et al.	438	612
*	M	US-5640047	06-1997	Nakashima	257	738

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*	N	JP-06163751	06-1994	Japan	Nakakawai, Fujito	23	29
*	O	JP-06120364	04-1994	Japan	Hirakawa, Tetsuo	23	10
*	P	JP-06151645	05-1994	Japan	Saito, Kenichi	23	28
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	R						
	S						
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NON-PATENT DOCUMENTS

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